

Notice of References Cited		Application/Control No. 10/523,348	Applicant(s)/Patent Under Reexamination KOYANAGI ET AL.	
		Examiner ADAM COONEY	Art Unit 2444	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,097,722	08-2000	Graham et al.	370/395.21
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Elek et al. Admission Control Based on End-to-End Measurements [online], March 2000 [retrieved on 2010-06-15]. Retrieved from the Internet:< http://citeseerx.ist.psu.edu/viewdoc/summary?doi=10.1.1.41.8465 >.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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